



8-Channel/Dual 4-Channel, Monolithic CMOS Multiplexers

DG508A/DG509A/883B
1

1.0 SCOPE

- 1.1** This specification covers the detail requirements for two multiplexers with two configurations—8-channel single-ended and 4-channel differential. These circuits are processed in accordance with MIL-STD-883 and are fully compliant to paragraph 1.2.1.

It is highly recommended that this data sheet be used as a baseline for new military or aerospace source control drawings.

For typical applications and operating characteristics, consult Maxim's data books.

1.2 Part Numbers

Device	Part Number
-1	DG508A(X)/883B
-2	DG509A(X)/883B

1.3 Package

(X)	Package	Description
AK	J-16	16-Pin Ceramic Dual-In-Line Package (CERDIP)
AL	F-16	16-Pin Flat Package (FP)
AP	D-16	16-Pin Sidebrazed Ceramic Package (Ceramic SB)
AZ	L-20	20-Pin Leadless Chip Carrier (LCC)

Note: See *Package Information* section for package drawings and dimensions.

1.4 Absolute Maximum Ratings

($T_A = +25^\circ\text{C}$, unless otherwise noted.)

V+ to V-44V
V+ to GND22V
V- to GND	-.25V
Digital Inputs, Vs or Vd (V- - 2V) to (V+ + 2V) or 20mA (whichever comes first)	
Continuous Current (any terminal except S or D)	30mA
Continuous Current, S or D	20mA
Peak Current, S or D (pulsed at 1ms, 10% duty cycle max)	40mA
Power Dissipation ($T_A = +70^\circ\text{C}$, $T_j = +150^\circ\text{C}$)		
16-Pin CERDIP (derate 10.00mW/°C above +70°C)	800mW
16-Pin FP (derate 6.06mW/°C above +70°C)	485mW
16-Pin Ceramic SB (derate 10.53mW/°C above +70°C)	842mW
20-Pin LCC (derate 9.09mW/°C above +70°C)	727mW
Operating Temperature Range	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (soldering, 10 sec)	+300°C

8-Channel/Dual 4-Channel, Monolithic CMOS Multiplexers

- 1.5 Thermal Resistance**
- $\Theta_{JC} = 50^{\circ}\text{C/W}$ for Q-16
 - $\Theta_{JC} = 55^{\circ}\text{C/W}$ for E-20
 - $\Theta_{JC} = 65^{\circ}\text{C/W}$ for F-16
 - $\Theta_{JC} = 45^{\circ}\text{C/W}$ for D-16
 - $\Theta_{JA} = 100^{\circ}\text{C/W}$ for Q-16
 - $\Theta_{JA} = 110^{\circ}\text{C/W}$ for E-20
 - $\Theta_{JA} = 165^{\circ}\text{C/W}$ for F-16
 - $\Theta_{JA} = 95^{\circ}\text{C/W}$ for D-16

2.0 REQUIREMENTS

2.1 Electrical performance characteristics are specified in Table 1 and apply over the full ambient operating temperature range, unless otherwise specified.

TABLE 1. ELECTRICAL PERFORMANCE CHARACTERISTICS (Note 1)

CHARACTERISTICS	SYMBOL	CONDITIONS	DEVICE TYPES	GROUP A SUB-GROUPS	LIMITS			UNITS
					MIN	TYP	MAX	
Analog-Signal Range	V_{ANALOG}	$V_S = \pm 15V$	All	1, 2, 3	-15		15	V
Drain-Source On Resistance	$r_{DS(ON)}$	$V_O = \pm 10V, I_S = -200\mu A$, sequence each switch on	All	1, 3			400	Ω
				2			500	
Drain-On Leakage Current	$I_{D(ON)}$	$V_S = V_D = \pm 10V$, sequence each switch on	-1	1	-10		10	μA
				2	-200		200	
			-2	1	-10		10	
				2	-100		100	
Drain-Off Leakage Current	$I_{D(OFF)}$	$V_D = \pm 10V, V_{EN} = 0V$ $V_S = \mp 10V$	-1	1	-10		10	μA
				2	-200		200	
			-2	1	-10		10	
				2	-100		100	
Source-Off Leakage Current	$I_{S(OFF)}$	$V_S = \pm 10V, V_D = \mp 10V$, $V_{EN} = 0V$	All	1	-1		1	μA
				2	-50		50	
Logic Input Current, Input Voltage High	I_{AH}	$V_A = 2.4V$	All	1	-10			μA
				2	-30			
		$V_A = 15V$		1			10	
				2			30	
Logic Input Current, Input Voltage Low	I_{AL}	$V_{EN} = 0V$ or $2.4V, V_A = 0V$	All	1	-10			μA
				2	-30			
Input Low Threshold	V_{AL}		All	1, 2, 3			0.8	V
Input High Threshold	V_{AH}		All	1, 2, 3	2.4			V
Positive Supply Current	I_+	$V_{EN} = 0V$ or $2.4V$	All	1			2.4	mA

8-Channel/Dual 4-Channel, Monolithic CMOS Multiplexers

DG508A/DG509A/883B 1

TABLE 1. ELECTRICAL PERFORMANCE CHARACTERISTICS (Note 1) (continued)

CHARACTERISTICS	SYMBOL	CONDITIONS	DEVICE TYPES	GROUP A SUB-GROUPS	LIMITS			UNITS
					MIN	TYP	MAX	
Negative Supply Current	I ₋	V _{EN} = 0V or 2.4V	All	1	-1.5			mA
Transition Time	t _{TRANS}	Figure 1	All	9		1		μs
				10, 11		1.5		
Break-Before-Make Time	t _{OPEN}	Figure 2	All	9	5			ns
Enable Turn-On Time	t _{ON(EN)}	Figure 3	All	9		1.5		μs
				10, 11		2.0		
Enable Turn-Off Time	t _{OFF(EN)}	Figure 3	All	9		1.0		μs
				10, 11		2.0		
Charge Injection (Note 2)	Q		All	4		20		pC
Off Isolation (Note 2)	V _{ISO}	V _{EN} = 0V, R _L = 1kΩ, C _L = 15pF, V _S = 7V _{RMS} , f = 500kHz	All	4		50		dB
Logic Input Capacitance (Note 2)	C _{IN}	f = 1MHz	All	4		5		pF
Source-Off Capacitance (Note 2)	C _{S(OFF)}	V _{EN} = V _S = 0V, f = 140kHz	All	4		6		pF
Drain-Off Capacitance (Note 2)	C _{D(OFF)}	V _{EN} = V _D = 0V, f = 140kHz	-1	4		25		pF
			-2			12		

Note 1: V₊ = 15V, V₋ = -15V, GND = 0V, V_{INH} = 2.4V, V_{INL} = 0.8V, unless otherwise noted.

Note 2: Typical limit for design aid only, not production tested.

3.0 QUALITY ASSURANCE

- 3.1** Sampling and inspection procedures shall be in accordance with MIL-M-38510 and, to the extent specified, with MIL-STD-883.
- 3.2** Screening shall be in accordance with Method 5004 of MIL-STD-883. Burn-in test (Method 1015):
- (1) Test condition A, B, C, or D.
 - (2) T_A = +125°C, minimum.
 - (3) Interim and final electrical test requirements shall be as specified in Table 2.
- 3.3** Quality conformance inspection shall be in accordance with Method 5005 of MIL-STD-883 including Groups A, B, C, and D inspection.
- Group A inspection:
- (1) Tests as specified in Table 2.
 - (2) Selected subgroups in Table 1, Method 5005 of MIL-STD-883 shall be omitted.

8-Channel/Dual 4-Channel, Monolithic CMOS Multiplexers

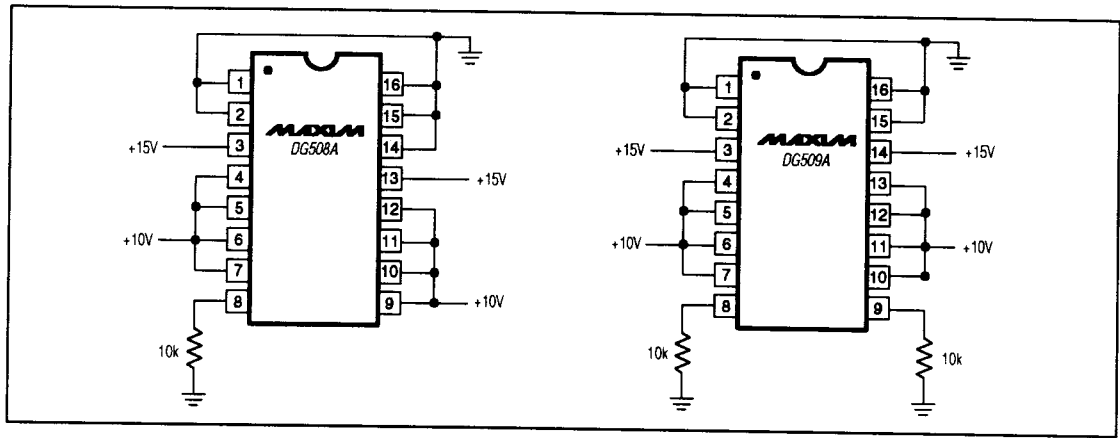
- 3.4 Groups C and D inspections:
- a. End-point electrical parameters shall be specified in Table 1.
 - b. Steady-state life test (Method 1005 of MIL-STD-883):
 - (1) Test condition A, B, C, or D.
 - (2) TA = +125°C, minimum.
 - (3) Test duration, 1000 hours, except as permitted by Method 1005 of MIL-STD-883.

TABLE 2. ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 Test Requirements	Subgroups (per Method 5005, Table 1)
Interim Electrical Parameters (Method 5004)	1
Final Electrical Parameters (Method 5004)	1,* 2, 3, 9
Group A Test Requirements (Method 5005)	1, 2, 3, 9, 10,** 11**
Groups C and D End-Point Electrical Parameters (Method 5005)	1

* PDA applies to Subgroup 1 only.
 ** Subgroups 10 and 11, if not tested, shall be guaranteed to the limits in Table 1.

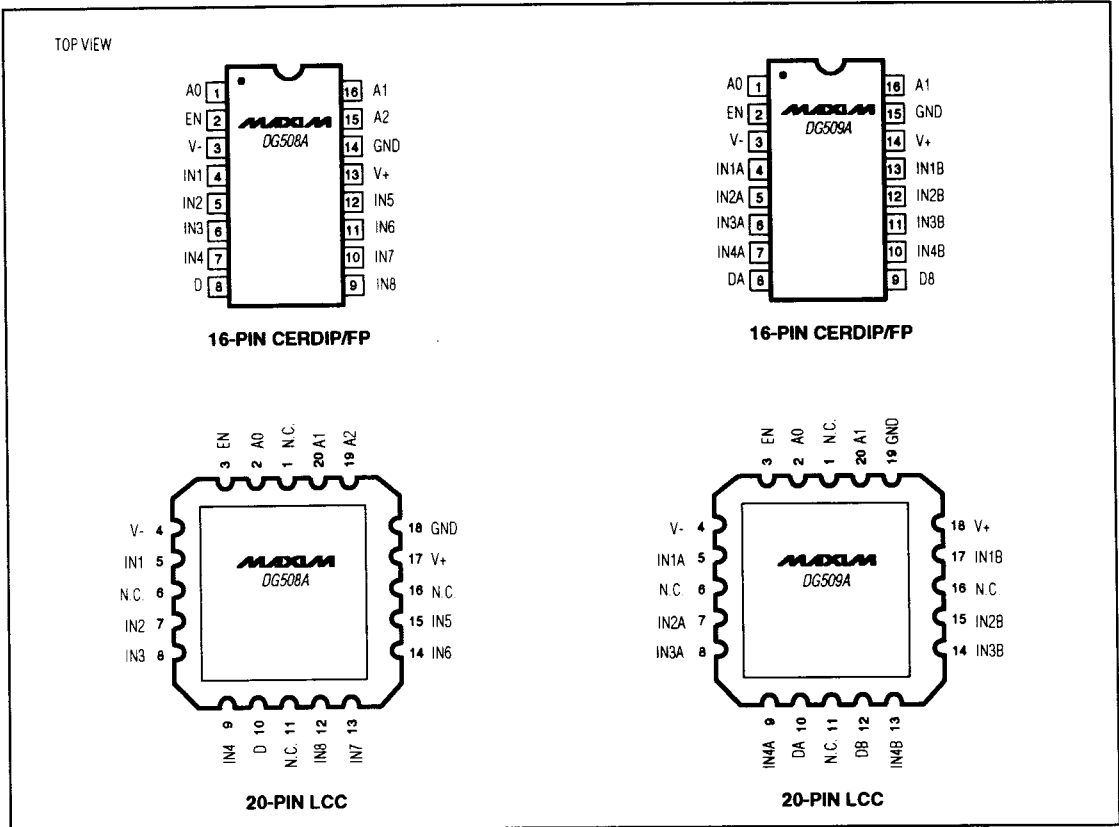
4.0 Life Test/Burn-In Circuits



8-Channel/Dual 4-Channel, Monolithic CMOS Multiplexers

DG508A/DG509A/883B

4.1 Pin Configurations



4.2 Truth Tables

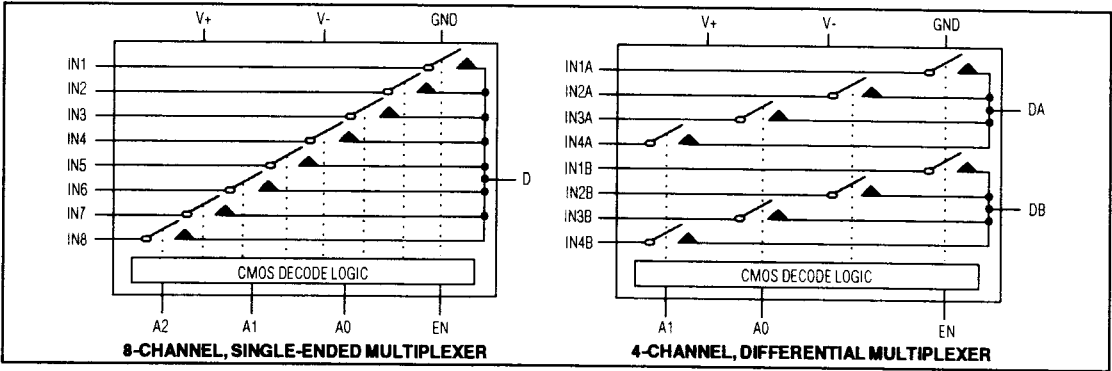
DG508A				
A2	A1	A0	EN	ON SWITCH
X	X	X	0	NONE
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

DG509A			
A1	A0	EN	ON SWITCH
X	X	0	NONE
0	0	1	1
0	1	1	2
1	0	1	3
1	1	1	4

Note: LOGIC '0' = $V_{AL} \leq 0.8V$, LOGIC '1' = $V_{AH} \geq 2.4V$.

8-Channel/Dual 4-Channel, Monolithic CMOS Multiplexers

4.3 Functional Diagrams



4.4 Test Circuits

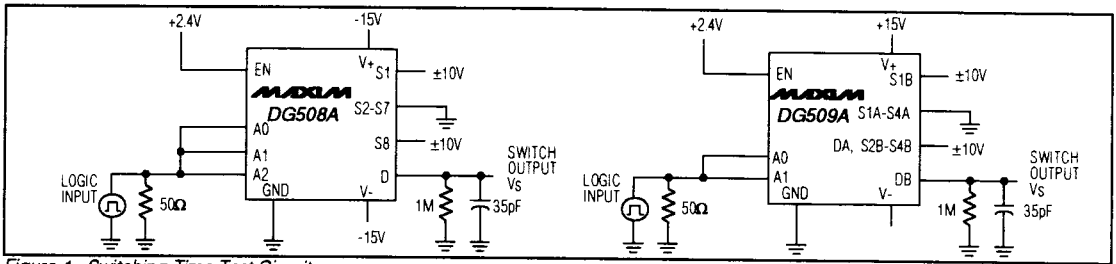


Figure 1. Switching-Time Test Circuits

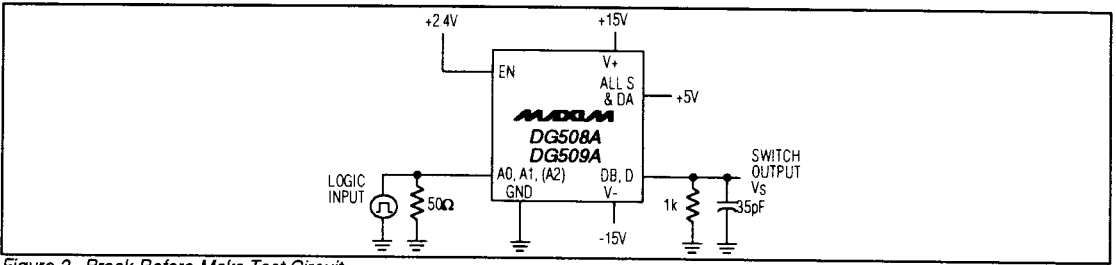


Figure 2. Break-Before-Make Test Circuit

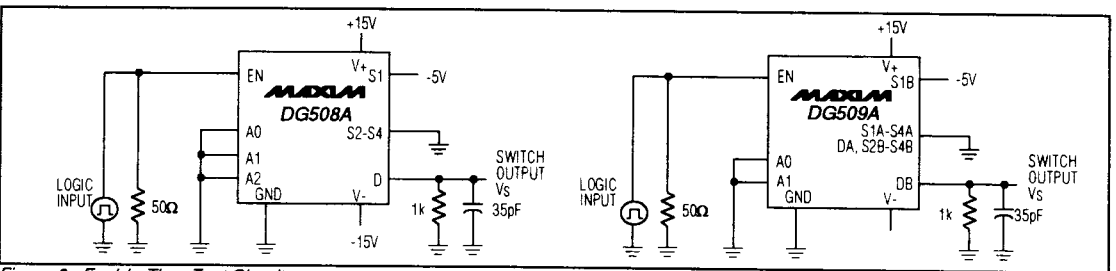


Figure 3. Enable-Time Test Circuits

Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time.